## Search Notes

Application/Control No.	Applicant(s)/Patent Under Reexamination
10562816	NAKANO ET AL.
Examiner	Art Unit
SHINLHON CHEN	2431

SEARCHED				
Class	Subclass	Date	Examiner	
713	175, 176, 156-158	3/17/09	S.C.	

SEARCH NOTES	
Date	Examiner
3/17/09	S.C.

INTERFERENCE SEARCH			
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